

**Notice of References Cited**

Application/Control No.

10/026,120

Applicant(s)/Patent Under  
Reexamination  
LI ET AL.

Examiner

Sin J Lee

Art Unit

1752

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2002/0061465 A1	05-2002	Hasegawa et al.	430/270.1
	B	US-5,304,453	04-1994	Lin	430/252
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
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	S					
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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